

Notice of References Cited	Application/Control No. 10/800,397	Applicant(s)/Patent Under Reexamination FLESCH ET AL.	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	D	US-6,442,432	08-2002	Lee, Michael Thomas	607/59
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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